

Preface
Introduction
Historical Background
Electrical Measurements
Interface states
Ultrahigh vacuum technology
Surface and interface analysis
Photoemission spectroscopy
Photoemission with soft X-rays
Particle - solid scattering
Electron energy loss spectroscopy
Rutherford backscattering spectrometry
Secondary ion mass spectrometry
Electron diffraction
Scanning tunneling microscopy
Optical spectroscopies
Cathodoluminescence spectroscopy
Electronic Material Surfaces
Adsorbates on Electronic Materials - Surfaces
Adsorbate - Semiconductor Sensor Applications
Heterojunctions
Metals on semiconductors
The future of electronic interfaces
Appendices
Symbols and abbreviations
Bibliography
Index

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